

ABSTRACT

Provided in the embodiments of the present application are a defect classification method and apparatus, and an electronic device and a storage medium. The method comprises: inputting an image to be subjected to detection and first position prompt information into a feature
5 extraction network of a defect classification model, so as to obtain an image feature of said image and a position identification feature, wherein the first position prompt information is used for indicating the position of a defect area in said image; and inputting the image feature and the position identification feature into a fully connected neural network of the defect
10 classification model, so as to obtain a defect classification result, wherein the defect classification result is used for indicating the category to which the defect area in said image belongs, and the defect classification model is an open-world semi-supervised learning model. By means of the solution, the interference of other areas in said image except the defect area on the defect classification result can be reduced, thereby improving the detection efficiency and the accuracy of the defect classification result.

Fig. 1